

S/N 09/834,751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al.

Examiner: Craig Steven Miller

Serial No.: 09/834,751

Group Art Unit: 2857

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Docket No.: 303.750US1

Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC
TESTING

AMENDMENT AND RESPONSE UNDER 37 CFR § 1.111

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

This paper responds to the Office Action mailed on January 26, 2006. Please amend the above-identified patent application as follows.